

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/710,341	TAKAHASHI ET AL.
Examiner	Art Unit	
Tran N. Nguyen	2834	

SEARCHED			
Class	Subclass	Date	Examiner
310	90 85	4/29/05	JRW
417	423.1	4/24/	
	423.3		
	423.5	105	JRW
	423.7		
	423.12		
	423.14		
	424.1		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
310	<i>all above</i>	<i>3/24/05</i>	<i>Jra</i>